Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/032,729	CHEN ET AL.
Examiner	Art Unit

2664

John L. Shew

SEARCHED				
Class	Subclass	Date	Examiner	
370	347,352	11/28/2005	JS	
	363,367			
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708	232,273	11/28/2005	JS	
709	230,236	11/28/2005	JS	
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	250			
710	310	11/28/2005	JS	

INTERFERENCE SEARCHED				
Subclass	Date	Examiner		
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